Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/604,277	BEDNAR ET AL.
Examiner	Art Unit
Binh C. Tat	2825

SEARCHED					
Class	Subclass	Date	Examiner		
716	8	2/3/2006	вт		
	-				

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
			-	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST SEARCH	2/3/2006	ВТ	
IEEE	2/3/2006	ВТ	